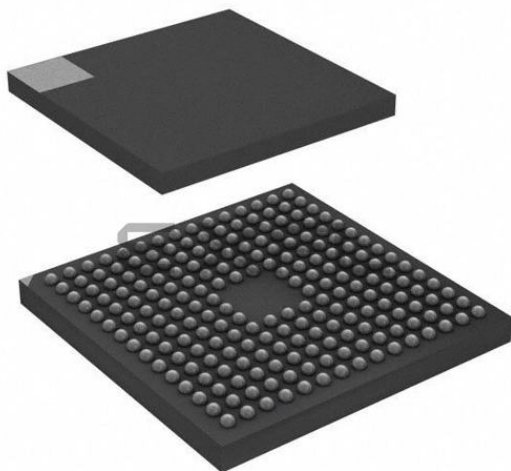




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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

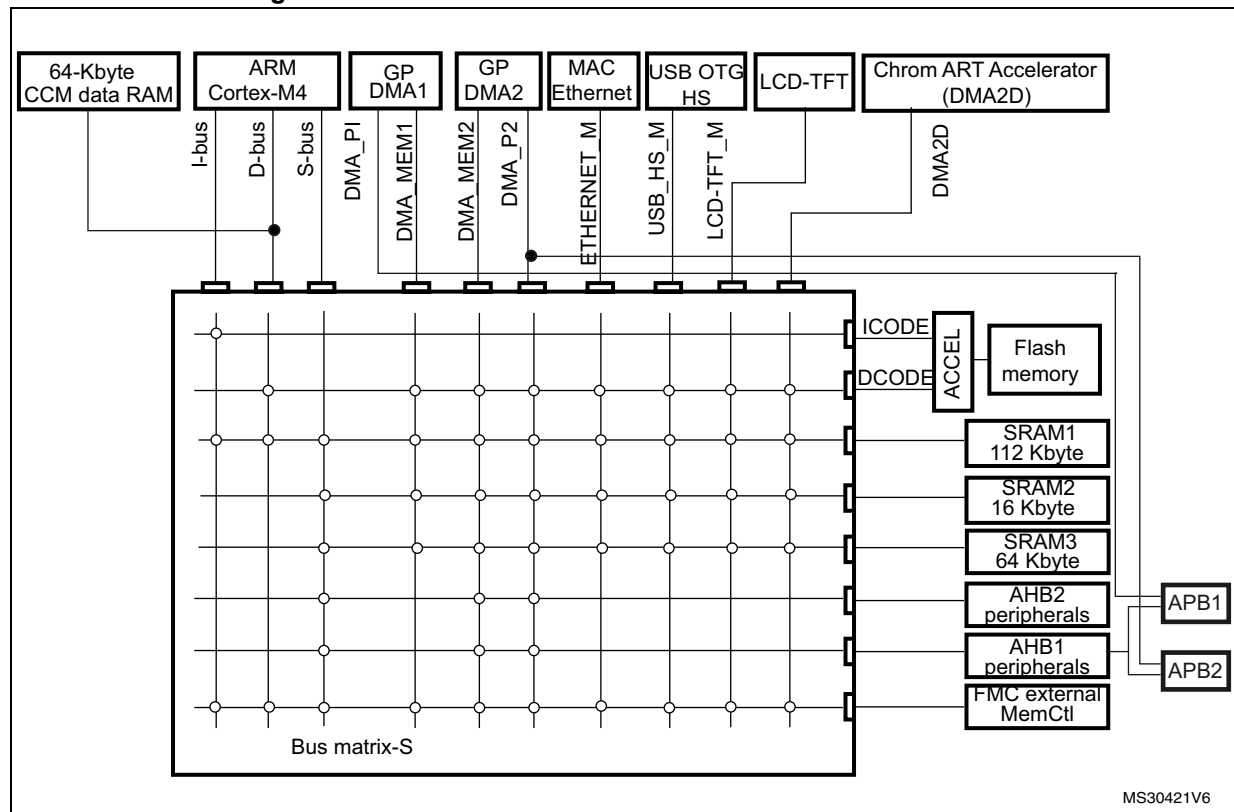
Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	180MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I ² C, IrDA, LINbus, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I ² S, LCD, POR, PWM, WDT
Number of I/O	168
Program Memory Size	2MB (2M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	256K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 24x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	216-TFBGA
Supplier Device Package	216-TFBGA (13x13)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f429nih6u

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Figure 5. STM32F427xx and STM32F429xx Multi-AHB matrix



3.8 DMA controller (DMA)

The devices feature two general-purpose dual-port DMAs (DMA1 and DMA2) with 8 streams each. They are able to manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers. They feature dedicated FIFOs for APB/AHB peripherals, support burst transfer and are designed to provide the maximum peripheral bandwidth (AHB/APB).

The two DMA controllers support circular buffer management, so that no specific code is needed when the controller reaches the end of the buffer. The two DMA controllers also have a double buffering feature, which automates the use and switching of two memory buffers without requiring any special code.

Each stream is connected to dedicated hardware DMA requests, with support for software trigger on each stream. Configuration is made by software and transfer sizes between source and destination are independent.

Table 6. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary output	Max interface clock (MHz)	Max timer clock (MHz) ⁽¹⁾
Advanced -control	TIM1, TIM8	16-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	Yes	90	180
General purpose	TIM2, TIM5	32-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	No	45	90/180
	TIM3, TIM4	16-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	No	45	90/180
	TIM9	16-bit	Up	Any integer between 1 and 65536	No	2	No	90	180
	TIM10, TIM11	16-bit	Up	Any integer between 1 and 65536	No	1	No	90	180
	TIM12	16-bit	Up	Any integer between 1 and 65536	No	2	No	45	90/180
	TIM13, TIM14	16-bit	Up	Any integer between 1 and 65536	No	1	No	45	90/180
Basic	TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No	45	90/180

1. The maximum timer clock is either 90 or 180 MHz depending on TIMPRE bit configuration in the RCC_DCKCFGR register.

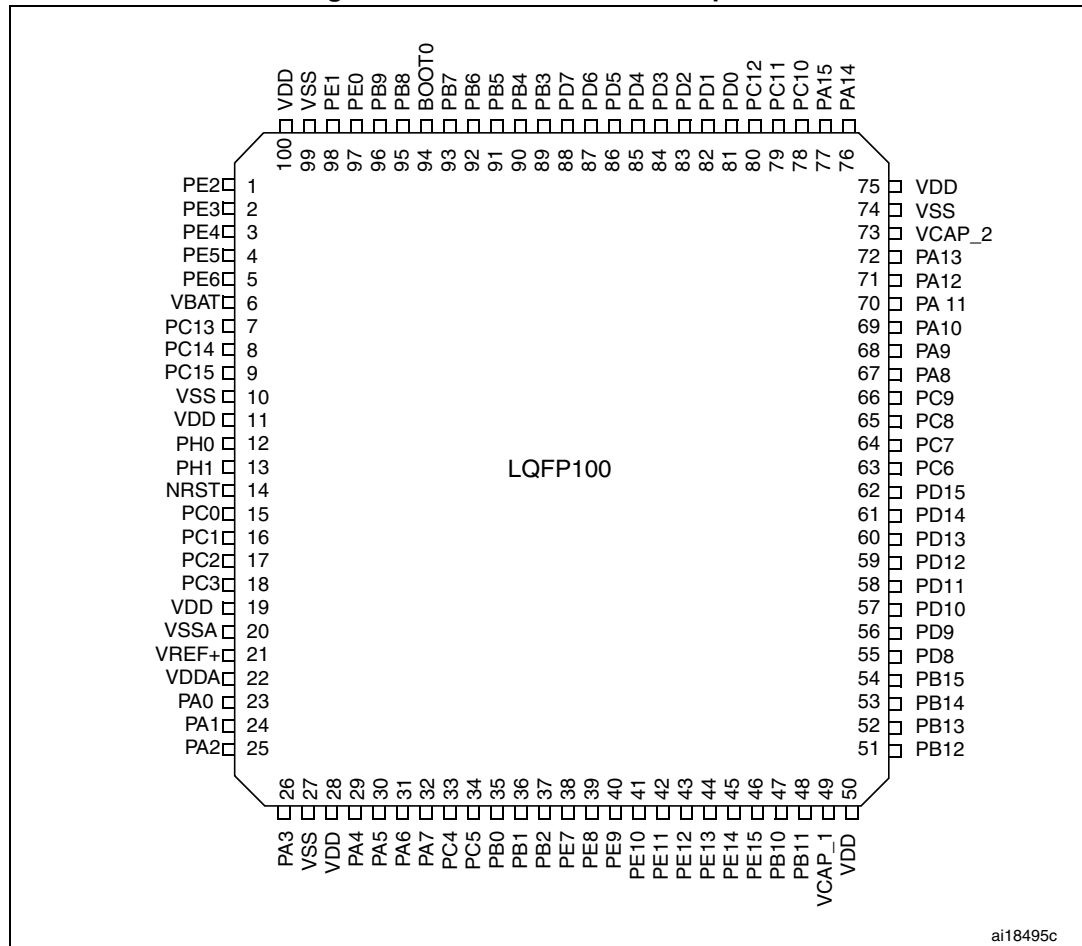
3.42 Embedded Trace Macrocell™

The ARM Embedded Trace Macrocell provides a greater visibility of the instruction and data flow inside the CPU core by streaming compressed data at a very high rate from the STM32F42x through a small number of ETM pins to an external hardware trace port analyzer (TPA) device. The TPA is connected to a host computer using USB, Ethernet, or any other high-speed channel. Real-time instruction and data flow activity can be recorded and then formatted for display on the host computer that runs the debugger software. TPA hardware is commercially available from common development tool vendors.

The Embedded Trace Macrocell operates with third party debugger software tools.

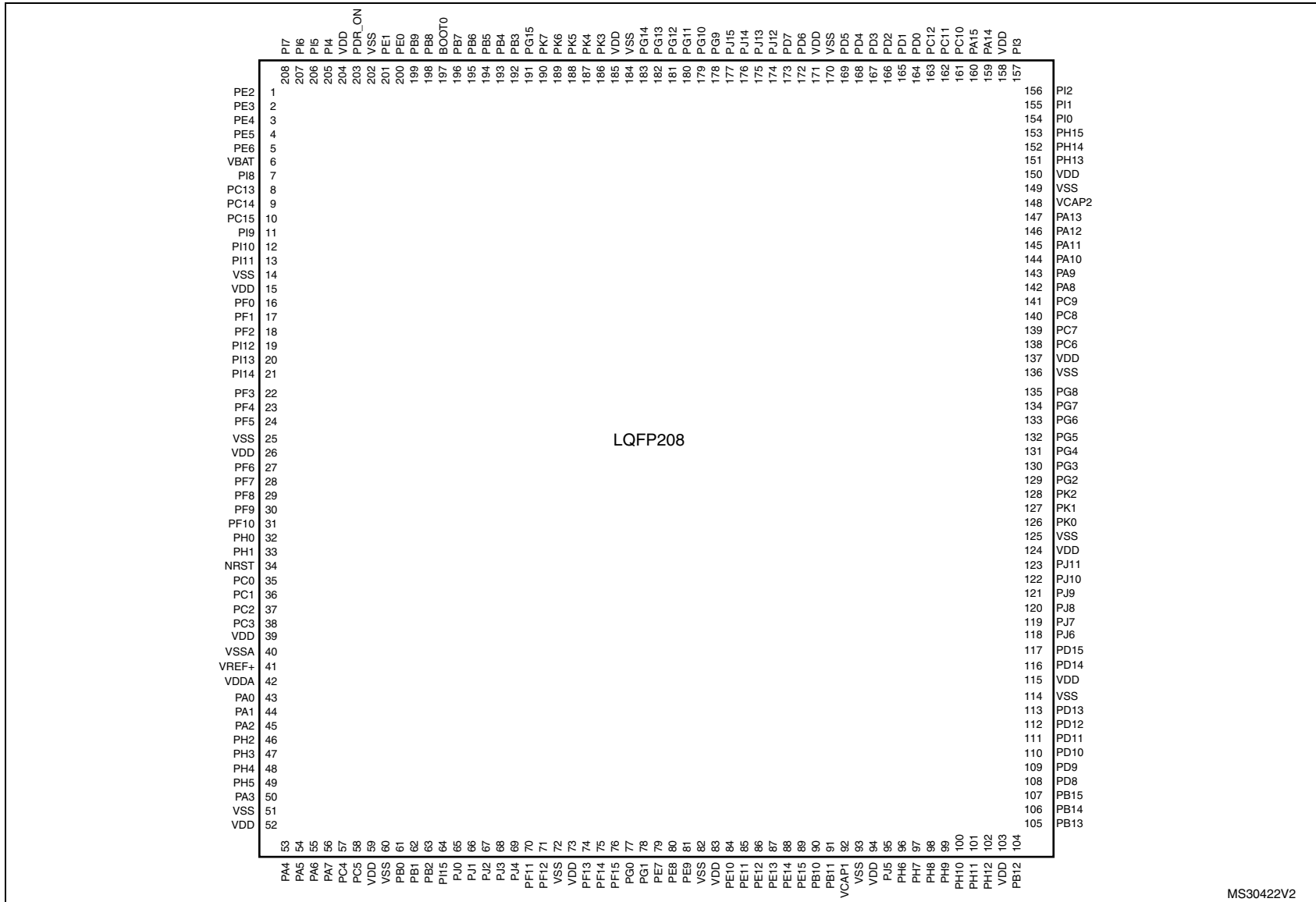
4 Pinouts and pin description

Figure 11. STM32F42x LQFP100 pinout



1. The above figure shows the package top view.

Figure 15. STM32F42x LQFP208 pinout



MS30422V2

1. The above figure shows the package top view.

Table 11. FMC pin definition (continued)

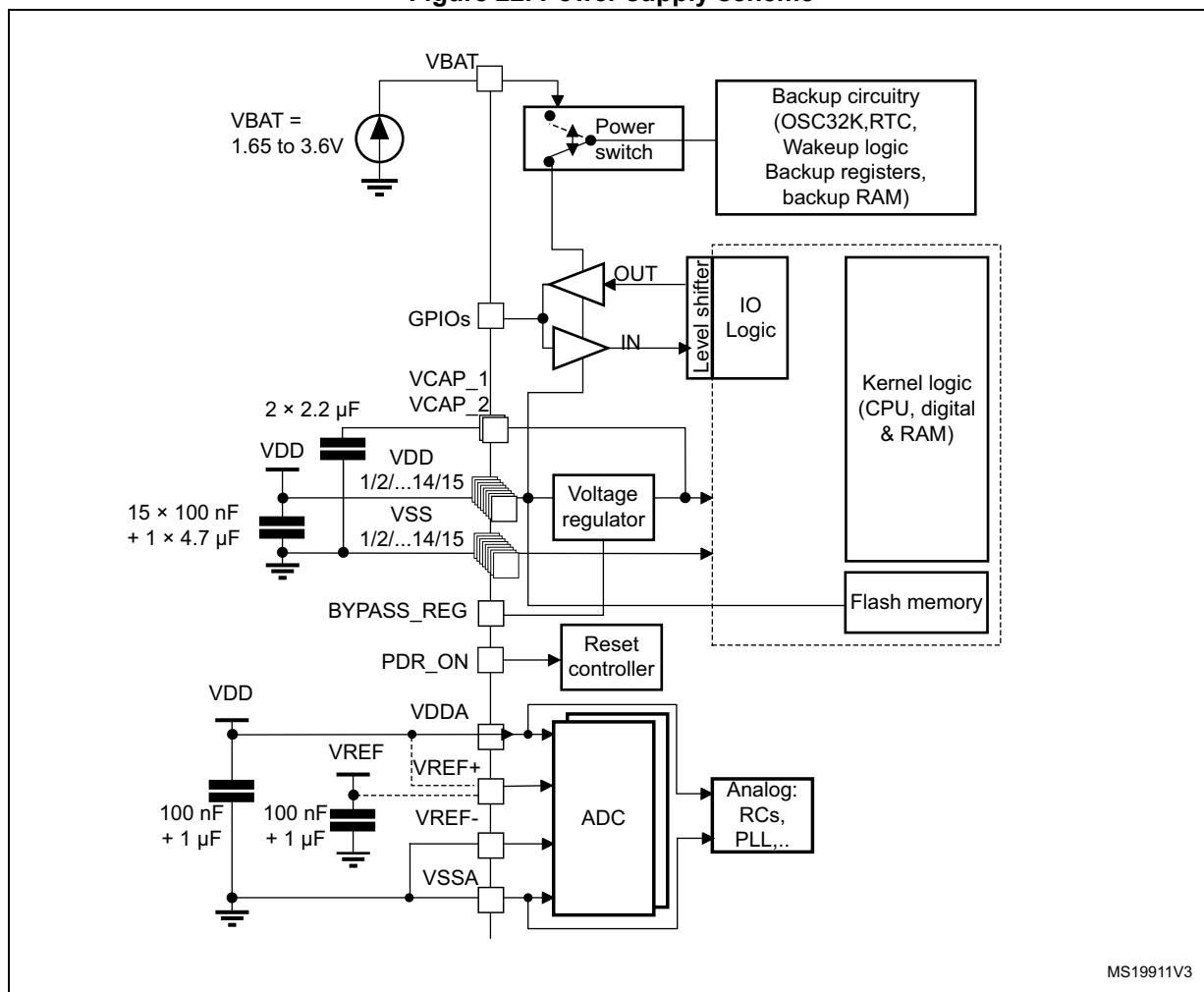
Pin name	CF	NOR/PSRAM/ SRAM	NOR/PSRAM Mux	NAND16	SDRAM
PE11	D8	D8	DA8	D8	D8
PE12	D9	D9	DA9	D9	D9
PE13	D10	D10	DA10	D10	D10
PE14	D11	D11	DA11	D11	D11
PE15	D12	D12	DA12	D12	D12
PD8	D13	D13	DA13	D13	D13
PD9	D14	D14	DA14	D14	D14
PD10	D15	D15	DA15	D15	D15
PH8		D16			D16
PH9		D17			D17
PH10		D18			D18
PH11		D19			D19
PH12		D20			D20
PH13		D21			D21
PH14		D22			D22
PH15		D23			D23
PI0		D24			D24
PI1		D25			D25
PI2		D26			D26
PI3		D27			D27
PI6		D28			D28
PI7		D29			D29
PI9		D30			D30
PI10		D31			D31
PD7		NE1	NE1	NCE2	
PG9		NE2	NE2	NCE3	
PG10	NCE4_1	NE3	NE3		
PG11	NCE4_2				
PG12		NE4	NE4		
PD3		CLK	CLK		
PD4	NOE	NOE	NOE	NOE	
PD5	NWE	NWE	NWE	NWE	
PD6	NWAIT	NWAIT	NWAIT	NWAIT	
PB7		NL(NADV)	NL(NADV)		

Table 12. STM32F427xx and STM32F429xx alternate function mapping (continued)

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		SYS	TIM1/2	TIM3/4/5	TIM8/9/ 10/11	I2C1/ 2/3	SPI1/2/ 3/4/5/6	SPI2/3/ SAI1	SPI3/ USART1/ 2/3	USART6/ UART4/5/7 /8	CAN1/2/ TIM12/13/14 /LCD	OTG_HS_ /OTG1_ FS	ETH	FMC/SDIO /OTG2_FS	DCMI	LCD	SYS
Port B	PB11	-	TIM2_ CH4	-	-	I2C2_ SDA	-	-	USART3_ RX	-	-	OTG_HS_ ULPI_D4	ETH_MII_ TX_EN/ ETH_RMII_ TX_EN	-	-	LCD_G5	EVEN TOUT
	PB12	-	TIM1_ BKIN	-	-	I2C2_ SMBA	SPI2_ NSS/I2 S2_WS	-	USART3_ CK	-	CAN2_RX	OTG_HS_ ULPI_D5	ETH_MII_ TXD0/ETH_ RMII_ TXD0	OTG_HS_ ID	-	-	EVEN TOUT
	PB13	-	TIM1_ CH1N	-	-	-	SPI2_ SCK/I2 S2_CK	-	USART3_ CTS	-	CAN2_TX	OTG_HS_ ULPI_D6	ETH_MII_ TXD1/ETH_ RMII_TX D1	-	-	-	EVEN TOUT
	PB14	-	TIM1_ CH2N	-	TIM8_ CH2N	-	SPI2_ MISO	I2S2ext_ SD	USART3_ RTS	-	TIM12_CH1	-	-	OTG_HS_ DM	-	-	EVEN TOUT
	PB15	RTC_ REFIN	TIM1_ CH3N	-	TIM8_ CH3N	-	SPI2_ MOSI/I2 S2_SD	-	-	-	TIM12_CH2	-	-	OTG_HS_ DP	-	-	EVEN TOUT
Port C	PC0	-	-	-	-	-	-	-	-	-	-	OTG_HS_ ULPI_STP	-	FMC_SDN WE	-	-	EVEN TOUT
	PC1	-	-	-	-	-	-	-	-	-	-	-	ETH_MDC	-	-	-	EVEN TOUT
	PC2	-	-	-	-	-	SPI2_ MISO	I2S2ext_ SD	-	-	-	OTG_HS_ ULPI_DIR	ETH_MII_ TXD2	FMC_ SDNE0	-	-	EVEN TOUT
	PC3	-	-	-	-	-	SPI2_ MOSI/I2 S2_SD	-	-	-	-	OTG_HS_ ULPI_NXT	ETH_MII_ TX_CLK	FMC_ SDCKE0	-	-	EVEN TOUT
	PC4	-	-	-	-	-	-	-	-	-	-	-	ETH_MII_ RXD0/ETH_ RMII_ RXD0	-	-	-	EVEN TOUT
	PC5	-	-	-	-	-	-	-	-	-	-	-	ETH_MII_ RXD1/ETH_ RMII_ RXD1	-	-	-	EVEN TOUT
	PC6	-	-	TIM3_ CH1	TIM8_ CH1	-	I2S2_ MCK	-	-	USART6_ TX	-	-	-	SDIO_D6	DCMI_ D0	LCD_ HSYNC	EVEN TOUT
	PC7	-	-	TIM3_ CH2	TIM8_ CH2	-	-	I2S3_ MCK	-	USART6_ RX	-	-	-	SDIO_D7	DCMI_ D1	LCD_G6	EVEN TOUT

6.1.6 Power supply scheme

Figure 22. Power supply scheme



1. To connect BYPASS_REG and PDR_ON pins, refer to [Section 3.17: Power supply supervisor](#) and [Section 3.18: Voltage regulator](#)
2. The two 2.2 µF ceramic capacitors should be replaced by two 100 nF decoupling capacitors when the voltage regulator is OFF.
3. The 4.7 µF ceramic capacitor must be connected to one of the V_{DD} pins.
4. V_{DDA}=V_{DD} and V_{SSA}=V_{SS}.

Caution: Each power supply pair (V_{DD}/V_{SS}, V_{DDA}/V_{SSA} ...) must be decoupled with filtering ceramic capacitors as shown above. These capacitors must be placed as close as possible to, or below, the appropriate pins on the underside of the PCB to ensure good operation of the device. It is not recommended to remove filtering capacitors to reduce PCB size or cost. This might cause incorrect operation of the device.

Table 22. reset and power control block characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$I_{RUSH}^{(1)}$	InRush current on voltage regulator power-on (POR or wakeup from Standby)		-	160	200	mA
$E_{RUSH}^{(1)}$	InRush energy on voltage regulator power-on (POR or wakeup from Standby)	$V_{DD} = 1.7\text{ V}$, $T_A = 105\text{ }^{\circ}\text{C}$, $I_{RUSH} = 171\text{ mA}$ for $31\text{ }\mu\text{s}$	-	-	5.4	μC

1. Guaranteed by design.
2. The reset temporization is measured from the power-on (POR reset or wakeup from V_{BAT}) to the instant when first instruction is read by the user application code.

6.3.6 Over-drive switching characteristics

When the over-drive mode switches from enabled to disabled or disabled to enabled, the system clock is stalled during the internal voltage set-up.

The over-drive switching characteristics are given in [Table 23](#). They are subject to general operating conditions for T_A .

Table 23. Over-drive switching characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Tod_swen	Over_drive switch enable time	HSI	-	45	-	μs
		HSE max for 4 MHz and min for 26 MHz	45	-	100	
		External HSE 50 MHz	-	40	-	
Tod_swdis	Over_drive switch disable time	HSI	-	20	-	
		HSE max for 4 MHz and min for 26 MHz.	20	-	80	
		External HSE 50 MHz	-	15	-	

1. Guaranteed by design.

I²S interface characteristics

Unless otherwise specified, the parameters given in [Table 63](#) for the I²S interface are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in [Table 17](#), with the following configuration:

- Output speed is set to $OSPEEDRy[1:0] = 10$
- Capacitive load $C = 30$ pF
- Measurement points are done at CMOS levels: $0.5V_{DD}$

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output alternate function characteristics (CK, SD, WS).

Table 63. I²S dynamic characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Max	Unit
f_{MCK}	I2S Main clock output	-	256x8K	256x F_S ⁽²⁾	MHz
f_{CK}	I2S clock frequency	Master data: 32 bits	-	64x F_S	MHz
		Slave data: 32 bits	-	64x F_S	
D_{CK}	I2S clock frequency duty cycle	Slave receiver	30	70	%
$t_{v(WS)}$	WS valid time	Master mode	0	6	ns
$t_{h(WS)}$	WS hold time	Master mode	0	-	
$t_{su(WS)}$	WS setup time	Slave mode	1	-	
$t_{h(WS)}$	WS hold time	Slave mode	0	-	
$t_{su(SD_MR)}$	Data input setup time	Master receiver	7.5	-	
$t_{su(SD_SR)}$		Slave receiver	2	-	
$t_{h(SD_MR)}$	Data input hold time	Master receiver	0	-	
$t_{h(SD_SR)}$		Slave receiver	0	-	
$t_{v(SD_ST)}$	Data output valid time	Slave transmitter (after enable edge)	-	27	
$t_{h(SD_ST)}$		Master transmitter (after enable edge)	-	20	
$t_{v(SD_MT)}$	Data output hold time	Master transmitter (after enable edge)	-	-	
$t_{h(SD_MT)}$		Master transmitter (after enable edge)	2.5	-	

1. Guaranteed by characterization results.

2. The maximum value of 256x F_S is 45 MHz (APB1 maximum frequency).

Note: Refer to the I2S section of RM0090 reference manual for more details on the sampling frequency (F_S).

f_{MCK} , f_{CK} , and D_{CK} values reflect only the digital peripheral behavior. The values of these parameters might be slightly impacted by the source clock precision. D_{CK} depends mainly on the value of ODD bit. The digital contribution leads to a minimum value of $(I2SDIV/(2*I2SDIV+ODD))$ and a maximum value of $(I2SDIV+ODD)/(2*I2SDIV+ODD)$. F_S maximum value is supported for each mode/condition.

USB OTG full speed (FS) characteristics

This interface is present in both the USB OTG HS and USB OTG FS controllers.

Table 65. USB OTG full speed startup time

Symbol	Parameter	Max	Unit
$t_{\text{STARTUP}}^{(1)}$	USB OTG full speed transceiver startup time	1	μs

1. Guaranteed by design.

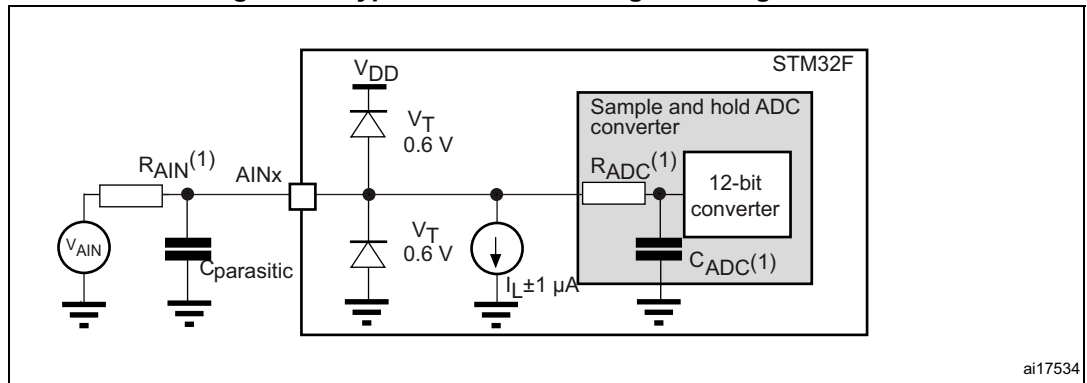
Table 66. USB OTG full speed DC electrical characteristics

Symbol		Parameter	Conditions	Min. ⁽¹⁾	Typ.	Max. ⁽¹⁾	Unit
Input levels	V _{DD}	USB OTG full speed transceiver operating voltage		3.0 ⁽²⁾	-	3.6	V
	V _{DI} ⁽³⁾	Differential input sensitivity	I(USB_FS_DP/DM, USB_HS_DP/DM)	0.2	-	-	V
	V _{CM} ⁽³⁾	Differential common mode range	Includes V _{DI} range	0.8	-	2.5	
	V _{SE} ⁽³⁾	Single ended receiver threshold		1.3	-	2.0	
Output levels	V _{OL}	Static output level low	R _L of 1.5 kΩ to 3.6 V ⁽⁴⁾	-	-	0.3	V
	V _{OH}	Static output level high	R _L of 15 kΩ to V _{SS} ⁽⁴⁾	2.8	-	3.6	
R _{PD}		PA11, PA12, PB14, PB15 (USB_FS_DP/DM, USB_HS_DP/DM)	V _{IN} = V _{DD}	17	21	24	kΩ
		PA9, PB13 (OTG_FS_VBUS, OTG_HS_VBUS)		0.65	1.1	2.0	
R _{PU}		PA12, PB15 (USB_FS_DP, USB_HS_DP)	V _{IN} = V _{SS}	1.5	1.8	2.1	
		PA9, PB13 (OTG_FS_VBUS, OTG_HS_VBUS)	V _{IN} = V _{SS}	0.25	0.37	0.55	

1. All the voltages are measured from the local ground potential.
2. The USB OTG full speed transceiver functionality is ensured down to 2.7 V but not the full USB full speed electrical characteristics which are degraded in the 2.7-to-3.0 V V_{DD} voltage range.
3. Guaranteed by design.
4. R_{L} is the load connected on the USB OTG full speed drivers.

Note: When VBUS sensing feature is enabled, PA9 and PB13 should be left at their default state (floating input), not as alternate function. A typical 200 μA current consumption of the sensing block (current to voltage conversion to determine the different sessions) can be observed on PA9 and PB13 when the feature is enabled.

Figure 51. Typical connection diagram using the ADC



ai17534

1. Refer to [Table 74](#) for the values of R_{AIN} , R_{ADC} and C_{ADC} .
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 5 pF). A high $C_{parasitic}$ value downgrades conversion accuracy. To remedy this, f_{ADC} should be reduced.

6.3.26 FMC characteristics

Unless otherwise specified, the parameters given in [Table 86](#) to [Table 101](#) for the FMC interface are derived from tests performed under the ambient temperature, f_{HCLK} frequency and V_{DD} supply voltage conditions summarized in [Table 17](#), with the following configuration:

- Output speed is set to $OSPEEDRy[1:0] = 10$ except at V_{DD} range 1.7 to 2.1V where $OSPEEDRy[1:0] = 11$
- Measurement points are done at CMOS levels: $0.5V_{DD}$

Refer to [Section 6.3.17: I/O port characteristics](#) for more details on the input/output characteristics.

Asynchronous waveforms and timings

[Figure 55](#) through [Figure 58](#) represent asynchronous waveforms and [Table 86](#) through [Table 93](#) provide the corresponding timings. The results shown in these tables are obtained with the following FMC configuration:

- AddressSetupTime = 0x1
- AddressHoldTime = 0x1
- DataSetupTime = 0x1 (except for asynchronous NWAIT mode , DataSetupTime = 0x5)
- BusTurnAroundDuration = 0x0
- For SDRAM memories, V_{DD} ranges from 2.7 to 3.6 V and maximum frequency FMC_SDCLK = 90 MHz
- For Mobile LPDDR SDRAM memories, V_{DD} ranges from 1.7 to 1.95 V and maximum frequency FMC_SDCLK = 84 MHz

Table 89. Asynchronous non-multiplexed SRAM/PSRAM/NOR write - NWAIT timings⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$8T_{HCLK}+1$	$8T_{HCLK}+2$	ns
$t_{w(NWE)}$	FMC_NWE low time	$6T_{HCLK}-1$	$6T_{HCLK}+2$	ns
$t_{su(NWAIT_NE)}$	FMC_NWAIT valid before FMC_NEx high	$6T_{HCLK}+1.5$	-	ns
$t_{h(NE_NWAIT)}$	FMC_NEx hold time after FMC_NWAIT invalid	$4T_{HCLK}+1$		ns

1. $C_L = 30$ pF.

2. Guaranteed by characterization results.

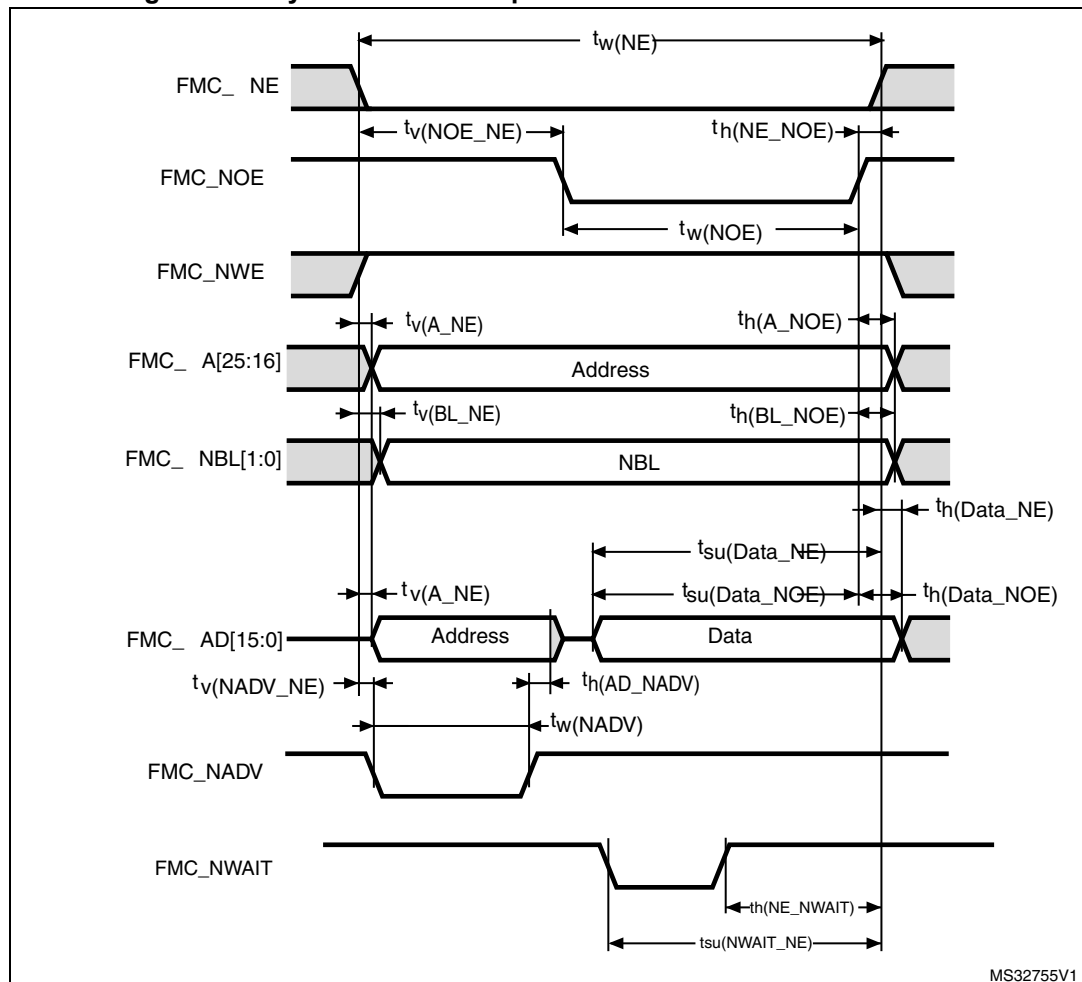
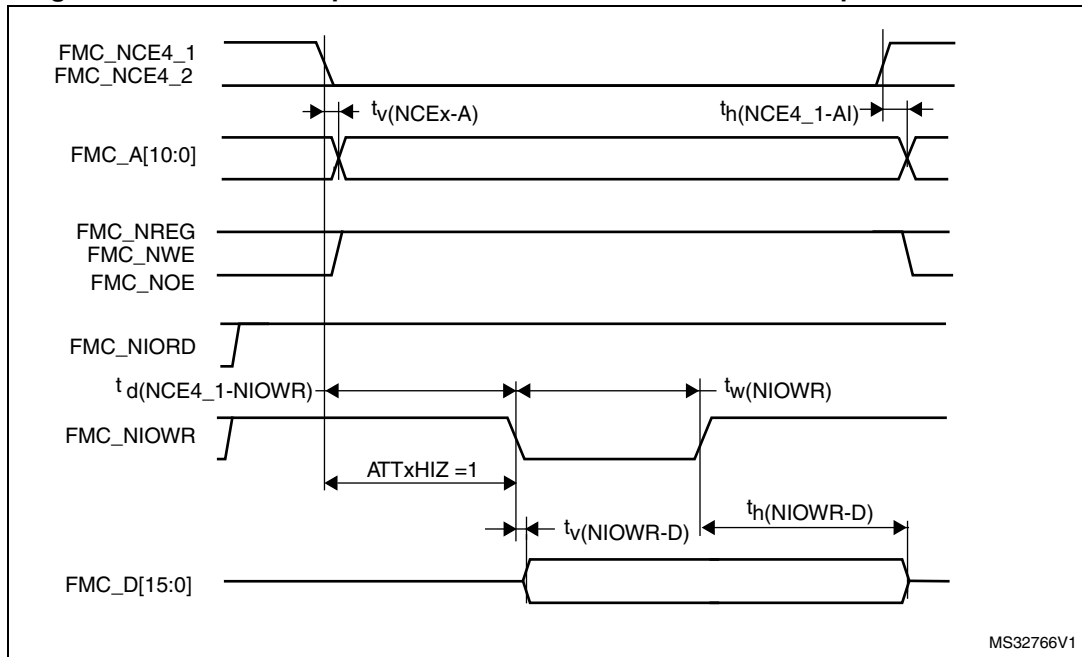
Figure 57. Asynchronous multiplexed PSRAM/NOR read waveforms

Figure 68. PC Card/CompactFlash controller waveforms for I/O space write access

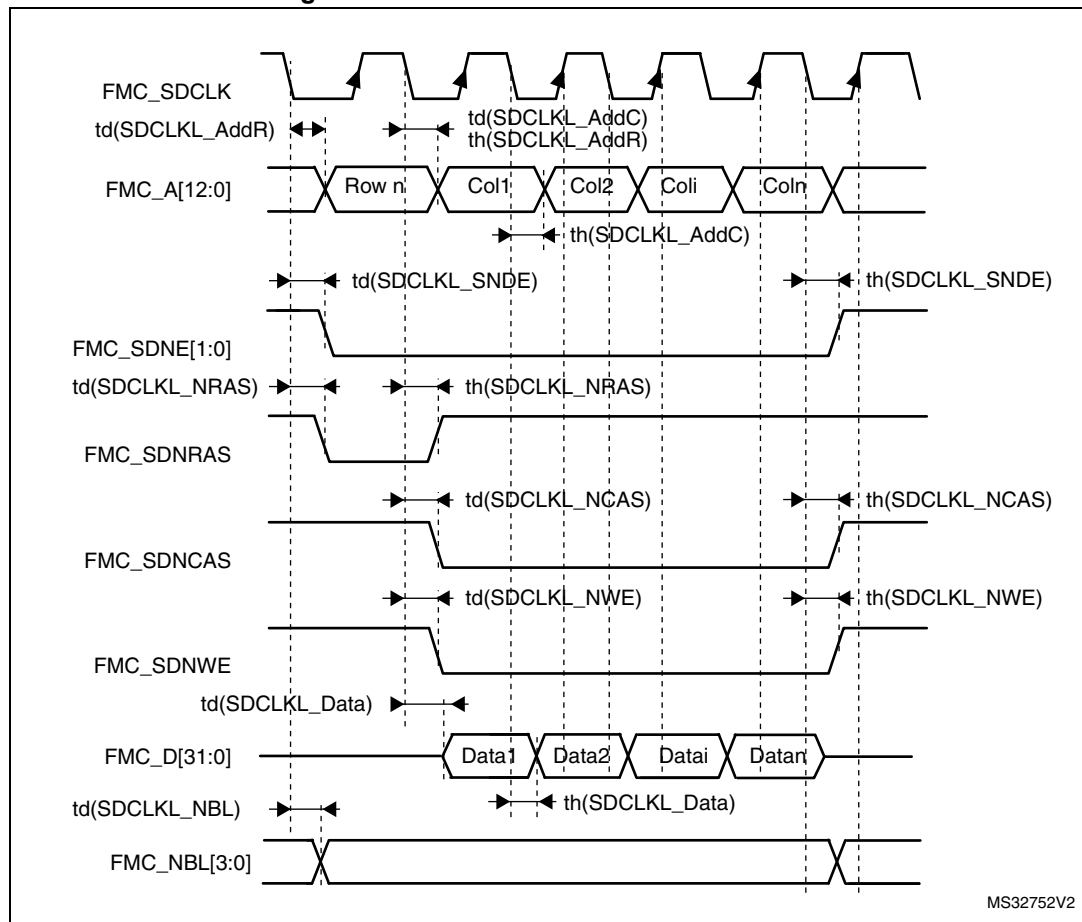
Table 98. Switching characteristics for PC Card/CF read and write cycles in attribute/common space⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$t_{v(NCEx-A)}$	FMC_Ncex low to FMC_Ay valid	-	0	ns
$t_{h(NCEx-AI)}$	FMC_NCEx high to FMC_Ax invalid	0	-	ns
$t_{d(NREG-NCEx)}$	FMC_NCEx low to FMC_NREG valid	-	1	ns
$t_{h(NCEx-NREG)}$	FMC_NCEx high to FMC_NREG invalid	$T_{HCLK} - 2$	-	ns
$t_{d(NCEx-NWE)}$	FMC_NCEx low to FMC_NWE low	-	$5T_{HCLK}$	ns
$t_{w(NWE)}$	FMC_NWE low width	$8T_{HCLK} - 0.5$	$8T_{HCLK} + 0.5$	ns
$t_{d(NWE-NCEx)}$	FMC_NWE high to FMC_NCEx high	$5T_{HCLK} + 1$	-	ns
$t_{v(NWE-D)}$	FMC_NWE low to FMC_D[15:0] valid	-	0	ns
$t_{h(NWE-D)}$	FMC_NWE high to FMC_D[15:0] invalid	$9T_{HCLK} - 0.5$	-	ns
$t_{d(D-NWE)}$	FMC_D[15:0] valid before FMC_NWE high	$13T_{HCLK} - 3$	-	ns
$t_{d(NCEx-NOE)}$	FMC_NCEx low to FMC_NOE low	-	$5T_{HCLK}$	ns
$t_{w(NOE)}$	FMC_NOE low width	$8T_{HCLK} - 0.5$	$8T_{HCLK} + 0.5$	ns
$t_{d(NOE-NCEx)}$	FMC_NOE high to FMC_NCEx high	$5T_{HCLK} - 1$	-	ns
$t_{su(D-NOE)}$	FMC_D[15:0] valid data before FMC_NOE high	T_{HCLK}	-	ns
$t_{h(NOE-D)}$	FMC_NOE high to FMC_D[15:0] invalid	0	-	ns

1. $C_L = 30$ pF.

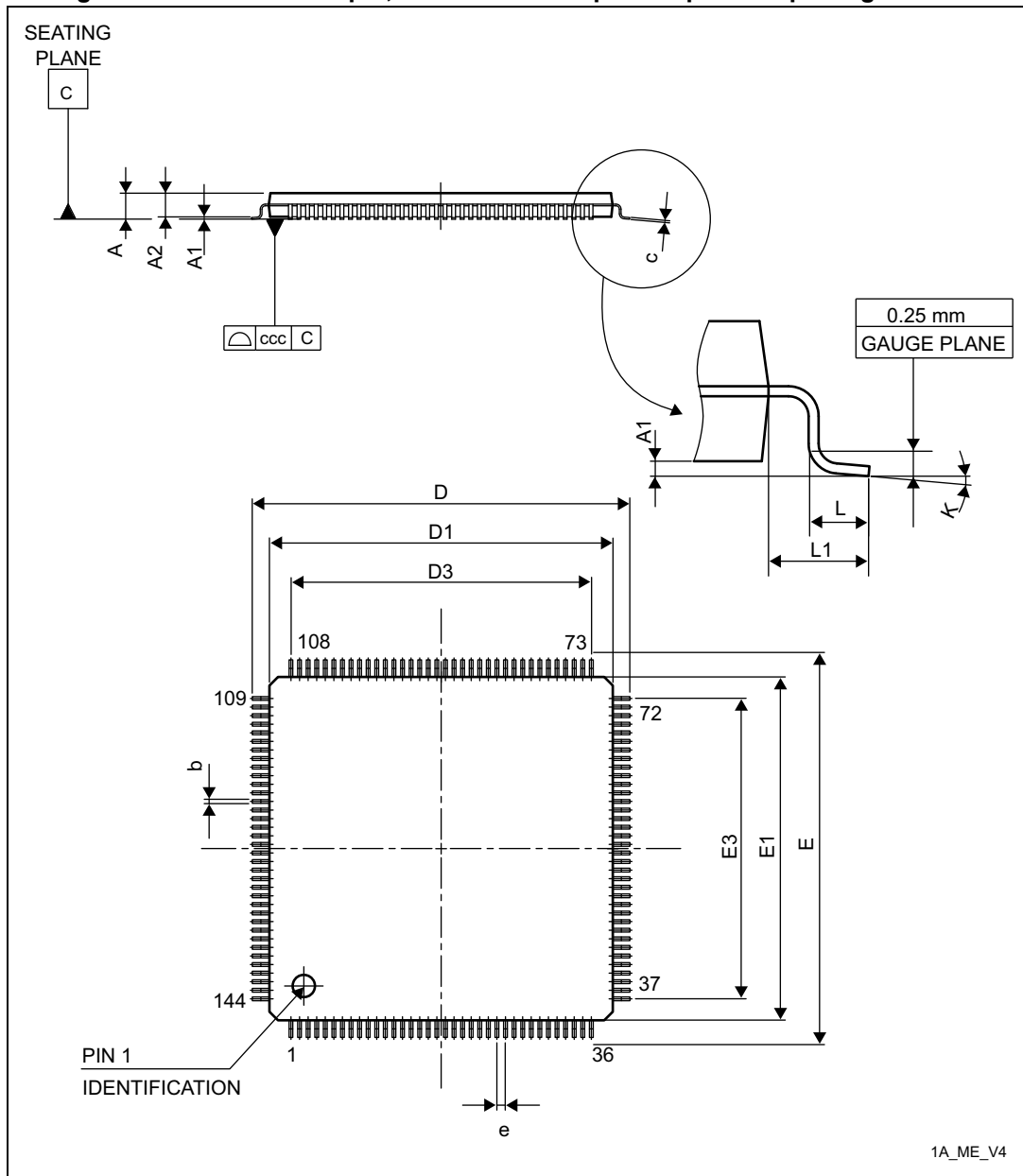
2. Guaranteed by characterization results.

Figure 74. SDRAM write access waveforms



7.3 LQFP144 package information

Figure 86. LQFP144-144-pin, 20 x 20 mm low-profile quad flat package outline



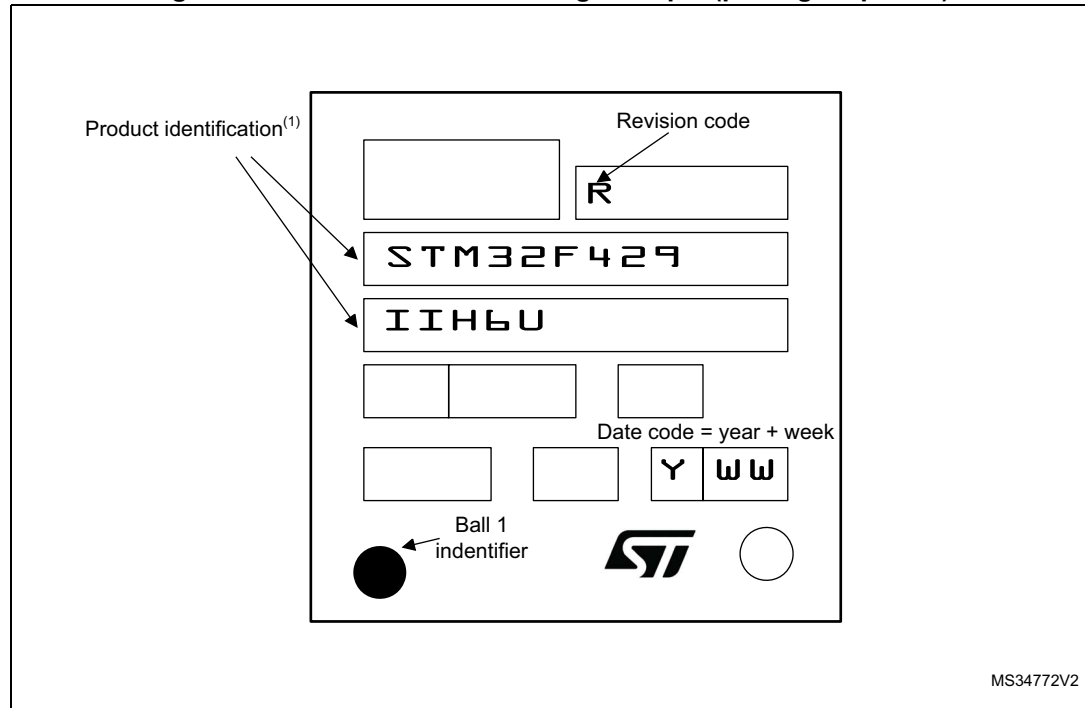
1. Drawing is not to scale.

Device marking for UFBGA176+25

The following figure gives an example of topside marking orientation versus ball A1 identifier location.

Other optional marking or inset/upset marks, which depends assembly location, are not indicated below.

Figure 100. UFBGA176+25 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Table 120. TFBGA216 - 216 ball 13 × 13 mm 0.8 mm pitch thin fine pitch ball grid array package mechanical data (continued)

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.080	-	-	0.0031

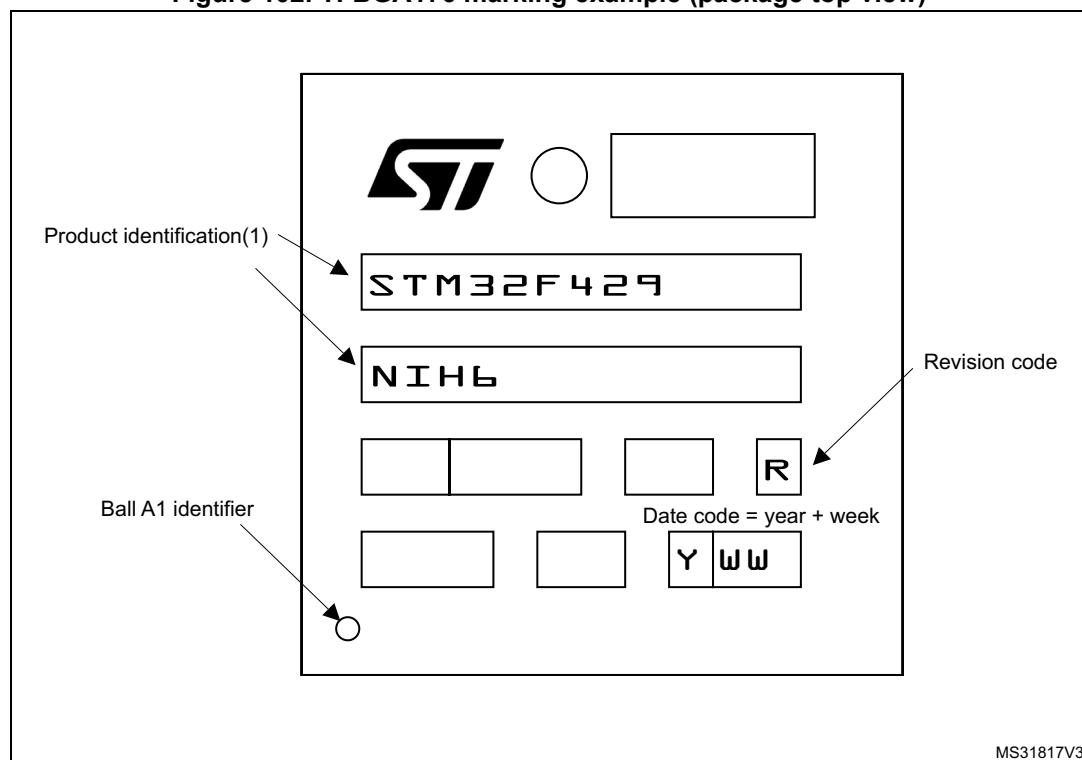
1. Values in inches are converted from mm and rounded to 4 decimal digits.

Device marking for TFBGA176

The following figure gives an example of topside marking orientation versus ball A1 identifier location.

Other optional marking or inset/upset marks, which depends assembly location, are not indicated below.

Figure 102. TFBGA176 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.